

December 2013

## IRF634B

## **N-Channel BFET MOSFET**

**250 V, 8.1 A, 450 m** $\Omega$ 

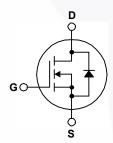
## **Description**

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar, DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switching DC/DC converters and switch mode power supplies.

### **Features**

- 8.1 A, 250 V,  $R_{DS(on)}$  = 450 m $\Omega$  @  $V_{GS}$  = 10 V
- Low Gate Charge (Typ. 29 nC)
- Low Crss (Typ. 20 pF)
- · Fast Switching
- · 100% Avalanche Tested
- · Improved dv/dt Capability





## Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted.

Symbol	Parameter		IRF634B_FP001	Unit	
V <sub>DSS</sub>	Drain-Source Voltage		250	V	
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C	C)	8.1	Α	
	- Continuous (T <sub>C</sub> = 100	°C)	5.1	Α	
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	32.4	Α	
V <sub>GSS</sub>	Gate-Source Voltage		± 30	V	
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	200	mJ	
I <sub>AR</sub>	Avalanche Current	(Note 1)	8.1	Α	
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	7.4	mJ	
dv/dt	Peak Diode Recovery dv/dt (Note 3)		4.8	V/ns	
$P_{D}$	Power Dissipation (T <sub>C</sub> = 25°C)		74	W	
	- Derate above 25°C		0.59	W/°C	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C	
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C	

## **Thermal Characteristics**

Symbol	Parameter	IRF634B_FP001	Unit	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Max.	1.69	°C/W	
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink, Max.	0.5	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient, Max.	62.5	°C/W	

## **Package Marking and Ordering Information**

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
IRF634B_FP001	IRF634B	TO-220	Tube	N/A	N/A	50 units

## **Flactrical Characteristics**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Cha	aracteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	250			V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, Referenced to 25°	C	0.27		V/°C
I <sub>DSS</sub>	Zana Oata Vallana Busin Ourset	V <sub>DS</sub> = 250 V, V <sub>GS</sub> = 0 V			10	μА
	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 200 V, T <sub>C</sub> = 125°C			100	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Cha	aracteristics					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		4.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 4.05 A		0.345	0.45	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 40 V, I <sub>D</sub> = 4.05 A		7.6		S
Dynam	ic Characteristics					
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$		780	1000	pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz		95	125	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			20	25	pF
Switchi	ing Characteristics					
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 125 V, I <sub>D</sub> = 8.1 A,		15	40	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$		75	160	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			100	210	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note	4)	65	140	ns
Qg	Total Gate Charge	V <sub>DS</sub> = 200 V, I <sub>D</sub> = 8.1 A,		29	38	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10 V	/	4.2		nC
Q <sub>gd</sub>	Gate-Drain Charge	(Note	4)	14	/	nC
Drain-S	Source Diode Characteristics a	nd Maximum Ratings				
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current				8.1	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current				32.4	Α
$V_{SD}$	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 8.1 \text{ A}$			1.5	V
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 8.1 \text{ A},$		170		ns
$Q_{rr}$	Reverse Recovery Charge	dI <sub>F</sub> / dt = 100 A/μs		0.91		μC

#### Notes:

**Notes:** 1. Repetitive rating: pulse-width limited by maximum junction temperature. 2. L = 4.9 mH, I $_{AS}$  = 8.1 A, V $_{DD}$  = 50 V, R $_{G}$  = 25  $\Omega$ , starting T $_{J}$  = 25°C. 3. I $_{SD}$  ≤ 8.1 A, di/dt ≤ 300 A/ $\mu$ s, V $_{DD}$  ≤ BV $_{DSS}$ , starting T $_{J}$  = 25°C. 4. Essentially independent of operating temperature.

## **Typical Characteristics**

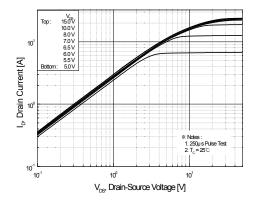


Figure 1. On-Region Characteristics

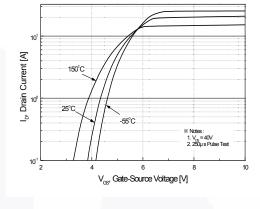


Figure 2. Transfer Characteristics

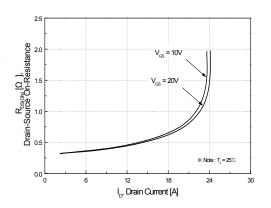


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

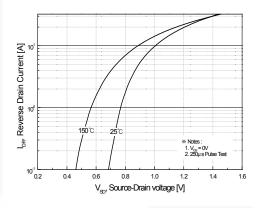


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

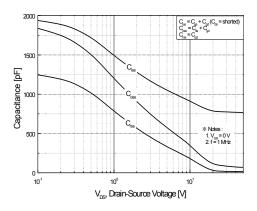


Figure 5. Capacitance Characteristics

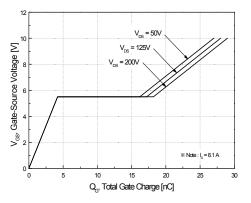


Figure 6. Gate Charge Characteristics

## Typical Characteristics (Continued)

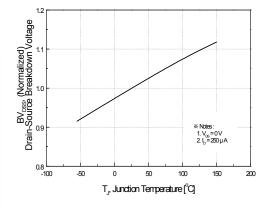
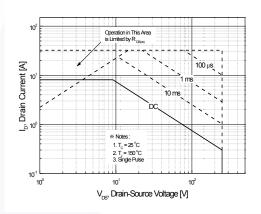


Figure 7. Breakdown Voltage Variation vs Temperature





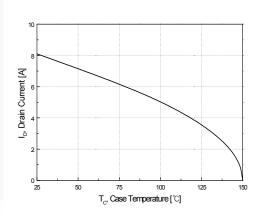


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs Case Temperature

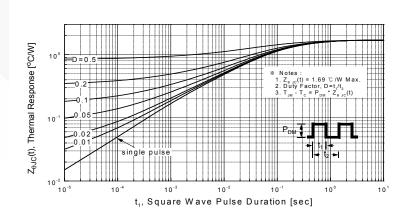


Figure 11. Transient Thermal Response Curve

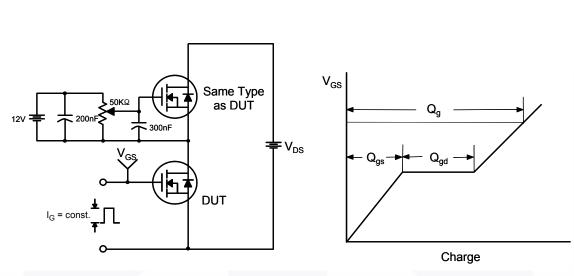


Figure 12. Gate Charge Test Circuit & Waveform

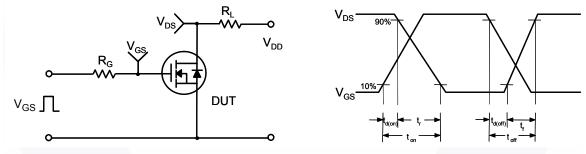


Figure 13. Resistive Switching Test Circuit & Waveforms

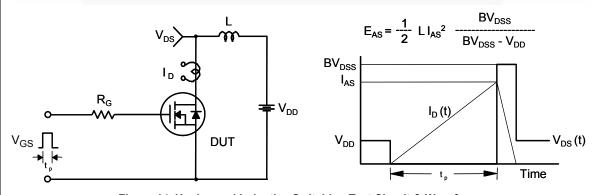
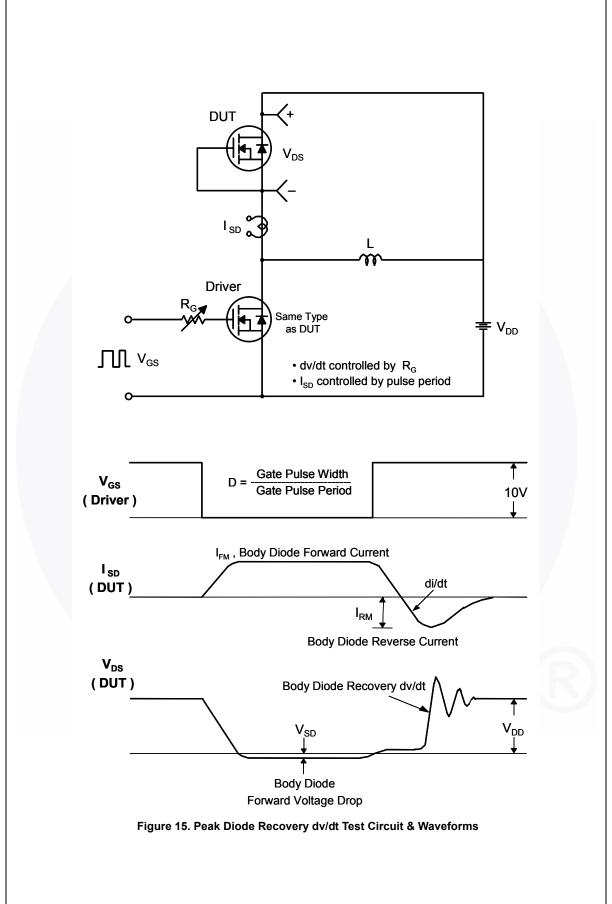


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms



## **Mechanical Dimensions**

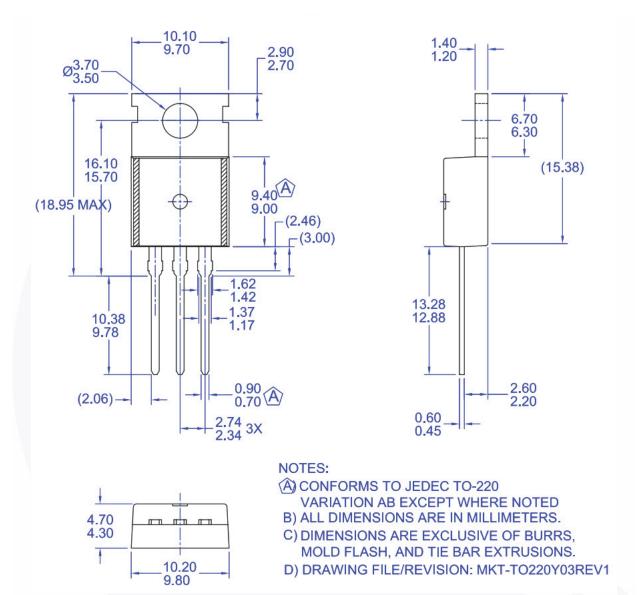


Figure 16. TO220, Molded, 3-Lead, Jedec Variation AB

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